

**Search Notes**

Application/Control No.

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Examiner

Hae M. Hyeon

Applicant(s)/Patent under  
Reexamination

KOPF ET AL.

Art Unit

2839

**SEARCHED**

Class	Subclass	Date	Examiner
Search	Updated	7/05	hnh
439	282	↓	↓

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR